



DMC4040SSD

40V COMPLEMENTARY PAIR ENHANCEMENT MODE MOSFET

Product Summary

Device	V _{(BR)DSS}	R _{DS(ON)} Max	I _D Max (A) T _A = +25°C (Notes 6 & 8)
Q1	40V	25mΩ @ V _{GS} = 10V	7.5
QI		40mΩ @ V _{GS} = 4.5V	6.2
Q2	40)/	25mΩ @ V _{GS} = -10V	-7.3
	-40V	45mΩ @ V _{GS} = -4.5V	-5.7

Features and Benefits

- Matched N & P R_{DS(ON)} Minimizes Power Losses
- Fast Switching Minimizes Switching Losses
- Dual Device Reduces PCB Area
- Totally Lead-Free & Fully RoHS Compliant (Notes 1 & 2)
- Halogen and Antimony Free. "Green" Device (Note 3)

Description

This MOSFET is designed to ensure that $R_{DS(ON)}$ of N and P channel FET are matched to minimize losses in both arms of the bridge. The DMC4040SSD is optimized for use in a 3-phase brushless DC motor circuit (BLDC), and CCFL backlighting.

Applications

- 3-Phase BLDC Motor
- CCFL Backlighting

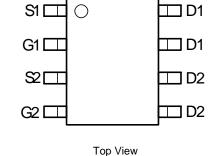
Mechanical Data

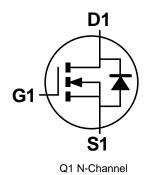
- Case: SO-8
- Case Material: Molded Plastic, "Green" Molding Compound.
 UL Flammability Classification Rating 94V-0
- Moisture Sensitivity: Level 1 per J-STD-020
- Terminals: Finish Matte Tin Annealed over Copper Leadframe.
 Solderable per MIL-STD-202, Method 208 (3)
- Weight: 0.074 grams (Approximate)

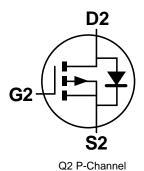
SO-8



Top View







Equivalent Circuit

Ordering Information (Note 4)

Product	Marking	Reel Size (inches)	Tape Width (mm)	Quantity per Reel
DMC4040SSD-13	C4040SD	13	12	2,500

Notes: 1. No purposely added lead. Fully EU Directive 2002/95/EC (RoHS) & 2011/65/EU (RoHS 2) compliant.

- 2. See http://www.diodes.com/quality/lead_free.html for more information about Diodes Incorporated's definitions of Halogen- and Antimony-free, "Green" and Lead-free.
- 3. Halogen- and Antimony-free "Green" products are defined as those which contain <900ppm bromine, <900ppm chlorine (<1500ppm total Br + Cl) and <1000ppm antimony compounds.
- 4. For packaging details, go to our website at http://www.diodes.com/products/packages.html.



Marking Information



⊃\\ = Manufacturer's MarkingC4040SD = Product Type Marking Code YYWW = Date Code Marking YY or \overline{YY} = Year (ex: 10 = 2010) WW = Week (01 - 53)

Maximum Ratings (@T_A = +25°C, unless otherwise specified.)

	Symbol	N-Channel - Q1	P-Channel - Q2	Unit		
Drain-Source Voltage	Drain-Source Voltage			40	-40	V
Gate-Source Voltage			V _{GSS}	±20	±20) v
		(Notes 6 & 8)		7.5	-7.5	
Continuous Drain Current	V _{GS} = 10V	T _A = +70°C (Notes 6 & 8)	I_D	5.8	-5.8	
		(Notes 5 & 8)		5.7	-5.7	
		(Notes 5 & 9)		6.8	-6.8	Α
Pulsed Drain Current	$V_{GS} = 10V$	(Notes 7 & 8)	I _{DM}	29.0	-29.0	
Continuous Source Current (Body Diode)		(Notes 6 & 8)	Is	3.0	-3.0	
Pulsed Source Current (Body Diode) (Notes 7		(Notes 7 & 8)	I _{SM}	29.0	-29.0	

Thermal Characteristics

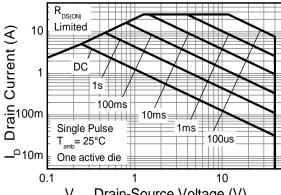
Characteristic	Symbol	N-Channel - Q1 P-Channel - Q2	Unit		
	(Notes 5 & 8)		1.25 10		
Power Dissipation Linear Derating Factor	(Notes 5 & 9)	P _D	1.8 14.3	W mW/°C	
, and the second	(Notes 6 & 8)		2.14 17.2		
	(Notes 5 & 8)		100	°C/W	
Thermal Resistance, Junction to Ambient	(Notes 5 & 9)	$R_{\theta JA}$	70		
	(Notes 6 & 8)		58		
Thermal Resistance, Junction to Lead	(Notes 5 & 10)	$R_{ heta JL}$	51		
Operating and Storage Temperature Range		T _J , T _{STG}	-55 to +150	°C	

Notes:

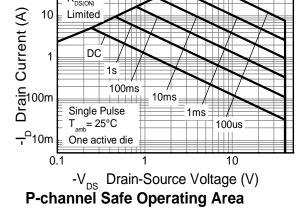
- 5. For a device surface mounted on 25mm x 25mm x 1.6mm FR4 PCB with high coverage of single sided 1oz copper, in still air conditions; the device is measured when operating in a steady-state condition.
- 6. Same as note (5), except the device is measured at $t \le 10$ sec. 7. Same as note (5), except the device is pulsed with D = 0.02 and pulse width 300 μ s. 8. For a dual device with one active die.
- 9. For a device with two active die running at equal power.
- 10. Thermal resistance from junction to solder-point (at the end of the drain lead).

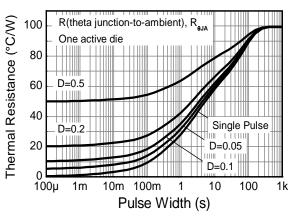


Thermal Characteristics (Continued)

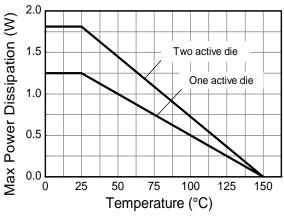


V_{DS} Drain-Source Voltage (V) **N-channel Safe Operating Area**





Transient Thermal Impedance



Derating Curve

Single Pulse T_{amb} = 25°C One active die

Pulse Power Dissipation



Electrical Characteristics (Q1 N-Channel) (@TA = +25°C, unless otherwise specified.)

Characteristic	Symbol	Min	Тур	Max	Unit	Test Condition	
OFF CHARACTERISTICS							
Drain-Source Breakdown Voltage	BV _{DSS}	40	_	_	V	$I_D = 250 \mu A, V_{GS} = 0V$	
Zero Gate Voltage Drain Current	I _{DSS}	_	_	1.0	μΑ	V _{DS} = 40V, V _{GS} = 0V	
Gate-Source Leakage	I _{GSS}	_		±100	nA	V _{GS} = ±20V, V _{DS} = 0V	
ON CHARACTERISTICS							
Gate Threshold Voltage	$V_{GS(th)}$	0.8	1.3	1.8	V	$I_D=250\mu A,\ V_{DS}=V_{GS}$	
Static Drain-Source On-Resistance (Note 11)	D		0.013	0.025	Ω	V _{GS} = 10V, I _D = 3A	
Static Drain-Source Off-Resistance (Note 11)	R _{DS(ON)}		0.028	0.040	12	$V_{GS} = 4.5V, I_D = 3A$	
Forward Transconductance (Notes 11 & 12)	G _{fs}	_	12.6	_	S	V _{DS} = 5V, I _D = 3A	
Diode Forward Voltage (Note 11)	V_{SD}	_	0.7	1.0	V	I _S = 1A, V _{GS} = 0V	
DYNAMIC CHARACTERISTICS (Note 12)							
Input Capacitance	Ciss	_	1,790	_		V 00V V 0V	
Output Capacitance	Coss	_	160	_	pF	V _{DS} = 20V, V _{GS} = 0V f= 1MHz	
Reverse Transfer Capacitance	C _{rss}	_	120	_		I= IIVII IZ	
Gate Resistance	R_g	_	1.03	_	Ω	V _{DS} = 0V, V _{GS} = 0V, f= 1MHz	
Total Gate Charge (Note 13)	Q_g	_	16.0	_		V _{GS} = 4.5V	
Total Gate Charge (Note 13)	Q_g	_	37.6	_	nC	V _{DS} = 20V	
Gate-Source Charge (Note 13)	Q_{gs}	_	7.8	_	IIC	V _{GS} = 10V I _D = 3A	
Gate-Drain Charge (Note 13)	Q_{gd}	_	6.6	_			
Turn-On Delay Time (Note 13)	t _{D(on)}	_	8.1	_		·	
Turn-On Rise Time (Note 13)	t _r	_	15.1	_	nS	V _{DD} = 20V, V _{GS} = 10V	
Turn-Off Delay Time (Note 13)	t _{D(off)}	_	24.3	_	110	I _D = 3A	
Turn-Off Fall Time (Note 13)	t _f		5.3	_			

Electrical Characteristics (Q2 P-Channel) (@TA = +25°C, unless otherwise specified.)

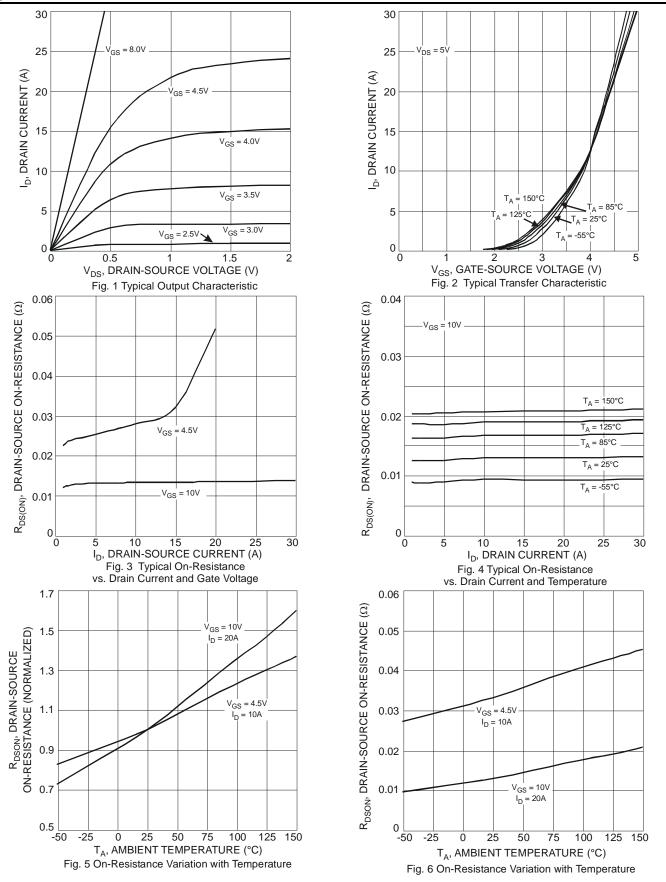
Characteristic	Symbol	Min	Тур	Max	Unit	Test Condition	
OFF CHARACTERISTICS							
Drain-Source Breakdown Voltage	BV _{DSS}	-40			V	$I_D = -250 \mu A$, $V_{GS} = 0 V$	
Zero Gate Voltage Drain Current	I _{DSS}	_	_	-1.0	μΑ	$V_{DS} = -40V, V_{GS}$; = 0V
Gate-Source Leakage	I _{GSS}	_	_	±100	nA	$V_{GS} = \pm 20V, V_{DS} = 0V$	
ON CHARACTERISTICS							
Gate Threshold Voltage	V _{GS(th)}	-0.8	-1.3	-1.8	V	$I_D = -250 \mu A, V_{DS}$	s = V _{GS}
Static Drain Source On Registence (Note 11)	7	_	0.018	0.025	Ω	V _{GS} = -10V, I _D = -3A	
Static Drain-Source On-Resistance (Note 11)	R _{DS(ON)}		0.030	0.045	Ω	$V_{GS} = -4.5V, I_{D} =$	= -3A
Forward Transconductance (Notes 11 & 12)	Gfs	_	16.6	_	S	V _{DS} = -5V, I _D = -3A	
Diode Forward Voltage (Note 11)	V _{SD}	_	-0.7	-1.0	V	$I_S = -1A, V_{GS} = 0V$	
DYNAMIC CHARACTERISTICS (Note 12)							
Input Capacitance	C _{iss}	_	1,643	_		$V_{DS} = -20V, V_{GS} = 0V$ f = 1MHz	
Output Capacitance	Coss	_	179	_	pF		
Reverse Transfer Capacitance	C _{rss}	_	128	_			
Gate Resistance	R_{g}	_	6.43	_	Ω	$V_{DS} = 0V, V_{GS} =$: 0V, f = 1MHz
Total Gate Charge (Note 13)	Qq	_	14.0	_		$V_{GS} = -4.5V$	
Total Gate Charge (Note 13)	Qq	_	33.7	_		$V_{DS} = -20V$ $I_{D} = -3A$	$V_{DS} = -20V$
Gate-Source Charge (Note 13)	Q _{gs}	_	5.5	_	nC		$I_D = -3A$
Gate-Drain Charge (Note 13)	Q _{qd}	_	7.3	_			
Turn-On Delay Time (Note 13)	t _{D(on)}	_	6.9	_	V _{DD} = -20V, V _{GS} = -10V		•
Turn-On Rise Time (Note 13)	tr	_	14.7	_			s = -10V
Turn-Off Delay Time (Note 13)	t _{D(off)}	_	53.7	_	nS	$I_D = -3A$	
Turn-Off Fall Time (Note 13)	t _f	_	30.9	_	7		

Notes:

- 11. Measured under pulsed conditions. Pulse width $\leq 300 \mu s;$ duty cycle $\leq 2\%$
- 12. For design aid only, not subject to production testing.
 13. Switching characteristics are independent of operating junction temperatures.



Typical Characteristics (Q1 N-Channel)







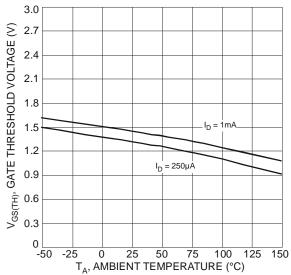
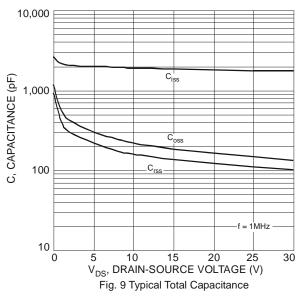
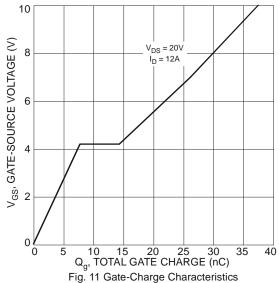
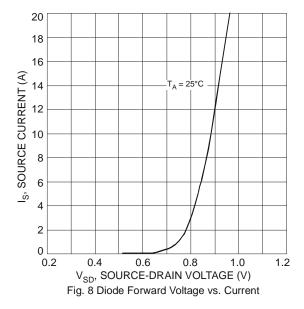
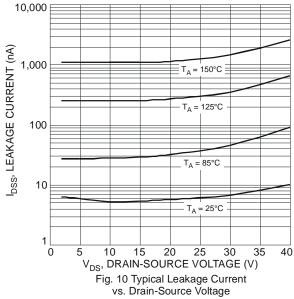


Fig. 7 Gate Threshold Variation vs. Ambient Temperature



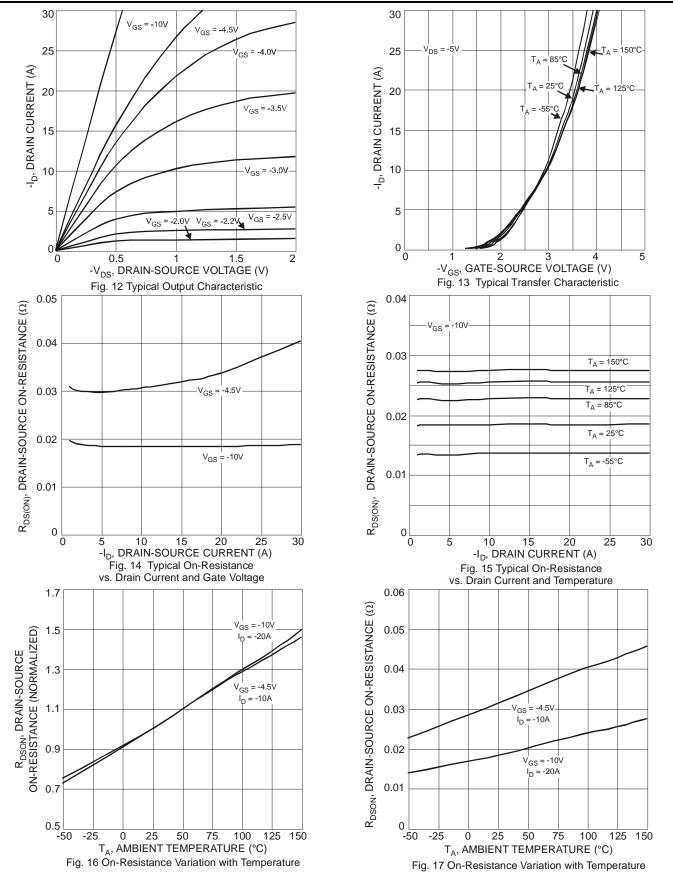








Typical Characteristics (Q2 P-Channel)







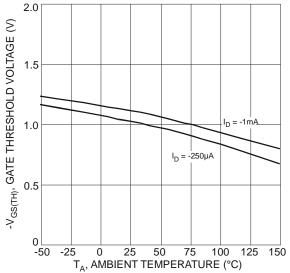
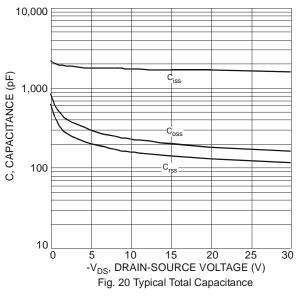
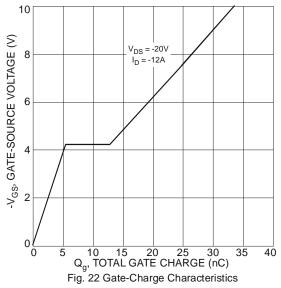
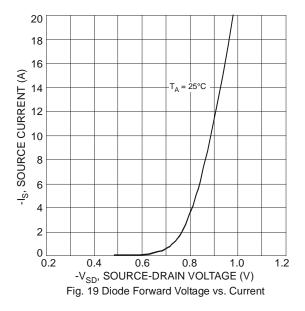
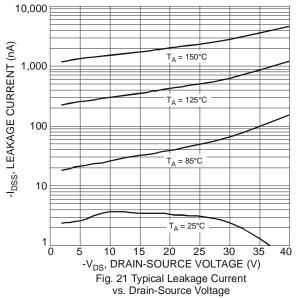


Fig. 18 Gate Threshold Variation vs. Ambient Temperature







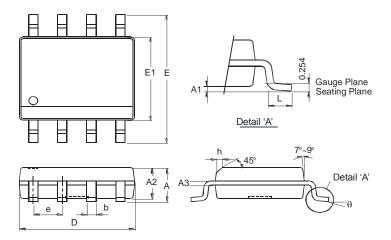




Package Outline Dimensions

Please see AP02002 at http://www.diodes.com/datasheets/ap02002.pdf for the latest version.

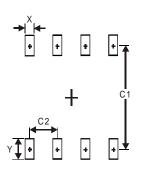




	SO-8					
Dim	Min	Max				
Α	_	1.75				
A1	0.10	0.20				
A2	1.30	1.50				
A3	0.15	0.25				
b	0.3	0.5				
D	4.85	4.95				
Е	5.90	6.10				
E1	3.85	3.95				
е	1.27 Typ					
h	— 0.35					
L	0.62	0.82				
θ	0° 8°					
All Dimensions in mm						

Suggested Pad Layout

Please see AP02001 at http://www.diodes.com/datasheets/ap02001.pdf for the latest version.



SO-8

Dimensions	Value (in mm)
Х	0.60
Y	1.55
C1	5.4
C2	1.27



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